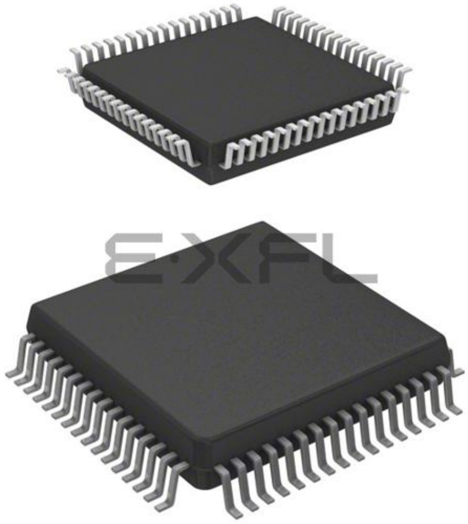

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Details	
Product Status	Active
Core Processor	S08
Core Size	8-Bit
Speed	40MHz
Connectivity	I²C, SCI, SPI
Peripherals	LVD, POR, PWM, WDT
Number of I/O	54
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-QFP
Supplier Device Package	64-QFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc9s08aw32cfue

Section Number	Title	Page

Chapter 1
Introduction

1.1 Overview

The MC9S08AW60, MC9S08AW48, MC9S08AW32, and MC9S08AW16 are members of the low-cost, high-performance HCS08 family of 8-bit microcontroller units (MCUs). All MCUs in the family use the enhanced HCS08 core and are available with a variety of modules, memory sizes, memory types, and package types. Refer to Table 1-1 for memory sizes and package types.

Table 1-2 summarizes the peripheral availability per package type for the devices available in the MC9S08AW60 Series.

Table 1-1. Devices in the MC9S08AW60 Series

Device	FLASH	RAM	Package
MC9S08AW60	63,280	2048	64 QFP 64 LQFP 48 QFN 44 LQFP
MC9S08AW48	49,152		
MC9S08AW32	32,768		
MC9S08AW16	16,384	1024	48 QFN 44 LQFP

Table 1-2. Peripherals Available per Package Type

	Package Options		
Feature	**64-pin**	**48-pin**	**44-pin**
ADC	16-channel	8-channel	8-channel
IIC	yes	yes	yes
IRQ	yes	yes	yes
KBI1	8	7	6
SCI1	yes	yes	yes
SCI2	yes	yes	yes
SPI1	yes	yes	yes
TPM1	6-channel	4-channel	4-channel
TPM1CLK	yes	no	no
TPM2	2-channel	2-channel	2-channel
TPM2CLK	yes	no	no
I/O pins	54	38	34

1.2 MCU Block Diagrams

The block diagram shows the structure of the MC9S08AW60 Series.

5.6 Low-Voltage Detect (LVD) System

The MC9S08AW60 Series includes a system to protect against low voltage conditions in order to protect memory contents and control MCU system states during supply voltage variations. The system is comprised of a power-on reset (POR) circuit and an LVD circuit with a user selectable trip voltage, either high (V_{LVDH}) or low (V_{LVDL}). The LVD circuit is enabled when LVDE in SPMSC1 is high and the trip voltage is selected by LVDV in SPMSC2. The LVD is disabled upon entering any of the stop modes unless the LVDSE bit is set. If LVDSE and LVDE are both set, then the MCU cannot enter stop2, and the current consumption in stop3 with the LVD enabled will be greater.

5.6.1 Power-On Reset Operation

When power is initially applied to the MCU, or when the supply voltage drops below the V_{POR} level, the POR circuit will cause a reset condition. As the supply voltage rises, the LVD circuit will hold the chip in reset until the supply has risen above the V_{LVDL} level. Both the POR bit and the LVD bit in SRS are set following a POR.

5.6.2 LVD Reset Operation

The LVD can be configured to generate a reset upon detection of a low voltage condition by setting LVDRE to 1. After an LVD reset has occurred, the LVD system will hold the MCU in reset until the supply voltage has risen above the level determined by LVDV. The LVD bit in the SRS register is set following either an LVD reset or POR.

5.6.3 LVD Interrupt Operation

When a low voltage condition is detected and the LVD circuit is configured for interrupt operation (LVDE set, LVDIE set, and LVDRE clear), then LVDF will be set and an LVD interrupt will occur.

5.6.4 Low-Voltage Warning (LVW)

The LVD system has a low voltage warning flag to indicate to the user that the supply voltage is approaching, the LVD voltage. The LVW does not have an interrupt associated with it. There are two user selectable trip voltages for the LVW, one high (V_{LVWH}) and one low (V_{LVWL}). The trip voltage is selected by LVWV in SPMSC2. Setting the LVW trip voltage equal to the LVD trip voltage is not recommended. Typical use of the LVW would be to select V_{LVWH} and V_{LVDL}.

5.7 Real-Time Interrupt (RTI)

The real-time interrupt function can be used to generate periodic interrupts. The RTI can accept two sources of clocks, the 1-kHz internal clock or an external clock if available. The 1-kHz internal clock source is completely independent of any bus clock source and is used only by the RTI module and, on some MCUs, the COP watchdog. To use an external clock source, it must be available and active. The RTICLKS bit in SRTISC is used to select the RTI clock source.

Table 5-3. SRS Register Field Descriptions (continued)

Field	Description
2 ICG	**Internal Clock Generation Module Reset** — Reset was caused by an ICG module reset. 0 Reset not caused by ICG module. 1 Reset caused by ICG module.
1 LVD	**Low Voltage Detect** — If the LVDRE and LVDSE bits are set and the supply drops below the LVD trip voltage, an LVD reset will occur. This bit is also set by POR. 0 Reset not caused by LVD trip or POR. 1 Reset caused by LVD trip or POR.

5.9.3 System Background Debug Force Reset Register (SBDFR)

This register contains a single write-only control bit. A serial background command such as WRITE_BYTE must be used to write to SBDFR. Attempts to write this register from a user program are ignored. Reads always return $00.

	7	6	5	4	3	2	1	0
R	0	0	0	0	0	0	0	0
W								BDFR[1]
Reset	0	0	0	0	0	0	0	0

= Unimplemented or Reserved

1 BDFR is writable only through serial background debug commands, not from user programs.

Figure 5-4. System Background Debug Force Reset Register (SBDFR)

Table 5-4. SBDFR Register Field Descriptions

Field	Description
0 BDFR	**Background Debug Force Reset** — A serial background command such as WRITE_BYTE may be used to allow an external debug host to force a target system reset. Writing logic 1 to this bit forces an MCU reset. This bit cannot be written from a user program.

5.9.4 System Options Register (SOPT)

This register may be read at any time. Bits 3 and 2 are unimplemented and always read 0. This is a write-once register so only the first write after reset is honored. Any subsequent attempt to write to SOPT (intentionally or unintentionally) is ignored to avoid accidental changes to these sensitive settings. SOPT should be written during the user's reset initialization program to set the desired controls even if the desired settings are the same as the reset settings.

6.4 Parallel I/O Control

Reading and writing of parallel I/O is done through the port data registers. The direction, input or output, is controlled through the port data direction registers. The parallel I/O port function for an individual pin is illustrated in the block diagram below.

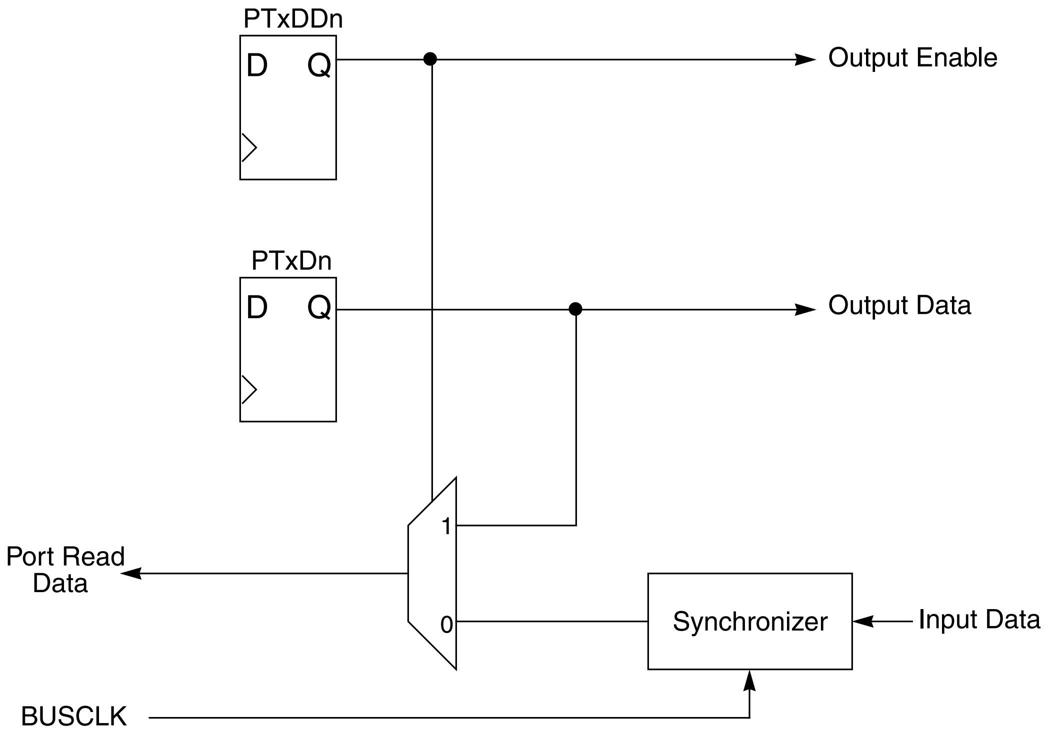


Figure 6-8. Parallel I/O Block Diagram

The data direction control bits determine whether the pin output driver is enabled, and they control what is read for port data register reads. Each port pin has a data direction register bit. When PTxDDn = 0, the corresponding pin is an input and reads of PTxD return the pin value. When PTxDDn = 1, the corresponding pin is an output and reads of PTxD return the last value written to the port data register. When a peripheral module or system function is in control of a port pin, the data direction register bit still controls what is returned for reads of the port data register, even though the peripheral system has overriding control of the actual pin direction.

When a shared analog function is enabled for a pin, all digital pin functions are disabled. A read of the port data register returns a value of 0 for any bits which have shared analog functions enabled. In general, whenever a pin is shared with both an alternate digital function and an analog function, the analog function has priority such that if both the digital and analog functions are enabled, the analog function controls the pin.

It is a good programming practice to write to the port data register before changing the direction of a port pin to become an output. This ensures that the pin will not be driven momentarily with an old data value that happened to be in the port data register.

7.3.6.7 SP-Relative, 16-Bit Offset (SP2)

This variation of indexed addressing uses the 16-bit value in the stack pointer (SP) plus a 16-bit offset included in the instruction as the address of the operand needed to complete the instruction.

7.4 Special Operations

The CPU performs a few special operations that are similar to instructions but do not have opcodes like other CPU instructions. In addition, a few instructions such as STOP and WAIT directly affect other MCU circuitry. This section provides additional information about these operations.

7.4.1 Reset Sequence

Reset can be caused by a power-on-reset (POR) event, internal conditions such as the COP (computer operating properly) watchdog, or by assertion of an external active-low reset pin. When a reset event occurs, the CPU immediately stops whatever it is doing (the MCU does not wait for an instruction boundary before responding to a reset event). For a more detailed discussion about how the MCU recognizes resets and determines the source, refer to the Resets, Interrupts, and System Configuration chapter.

The reset event is considered concluded when the sequence to determine whether the reset came from an internal source is done and when the reset pin is no longer asserted. At the conclusion of a reset event, the CPU performs a 6-cycle sequence to fetch the reset vector from 0xFFFE and 0xFFFF and to fill the instruction queue in preparation for execution of the first program instruction.

7.4.2 Interrupt Sequence

When an interrupt is requested, the CPU completes the current instruction before responding to the interrupt. At this point, the program counter is pointing at the start of the next instruction, which is where the CPU should return after servicing the interrupt. The CPU responds to an interrupt by performing the same sequence of operations as for a software interrupt (SWI) instruction, except the address used for the vector fetch is determined by the highest priority interrupt that is pending when the interrupt sequence started.

The CPU sequence for an interrupt is:

1. Store the contents of PCL, PCH, X, A, and CCR on the stack, in that order.
2. Set the I bit in the CCR.
3. Fetch the high-order half of the interrupt vector.
4. Fetch the low-order half of the interrupt vector.
5. Delay for one free bus cycle.
6. Fetch three bytes of program information starting at the address indicated by the interrupt vector to fill the instruction queue in preparation for execution of the first instruction in the interrupt service routine.

After the CCR contents are pushed onto the stack, the I bit in the CCR is set to prevent other interrupts while in the interrupt service routine. Although it is possible to clear the I bit with an instruction in the interrupt service routine, this would allow nesting of interrupts (which is not recommended because it leads to programs that are difficult to debug and maintain).

For compatibility with the earlier M68HC05 MCUs, the high-order half of the H:X index register pair (H) is not saved on the stack as part of the interrupt sequence. The user must use a PSHH instruction at the beginning of the service routine to save H and then use a PULH instruction just before the RTI that ends the interrupt service routine. It is not necessary to save H if you are certain that the interrupt service routine does not use any instructions or auto-increment addressing modes that might change the value of H.

The software interrupt (SWI) instruction is like a hardware interrupt except that it is not masked by the global I bit in the CCR and it is associated with an instruction opcode within the program so it is not asynchronous to program execution.

7.4.3 Wait Mode Operation

The WAIT instruction enables interrupts by clearing the I bit in the CCR. It then halts the clocks to the CPU to reduce overall power consumption while the CPU is waiting for the interrupt or reset event that will wake the CPU from wait mode. When an interrupt or reset event occurs, the CPU clocks will resume and the interrupt or reset event will be processed normally.

If a serial BACKGROUND command is issued to the MCU through the background debug interface while the CPU is in wait mode, CPU clocks will resume and the CPU will enter active background mode where other serial background commands can be processed. This ensures that a host development system can still gain access to a target MCU even if it is in wait mode.

7.4.4 Stop Mode Operation

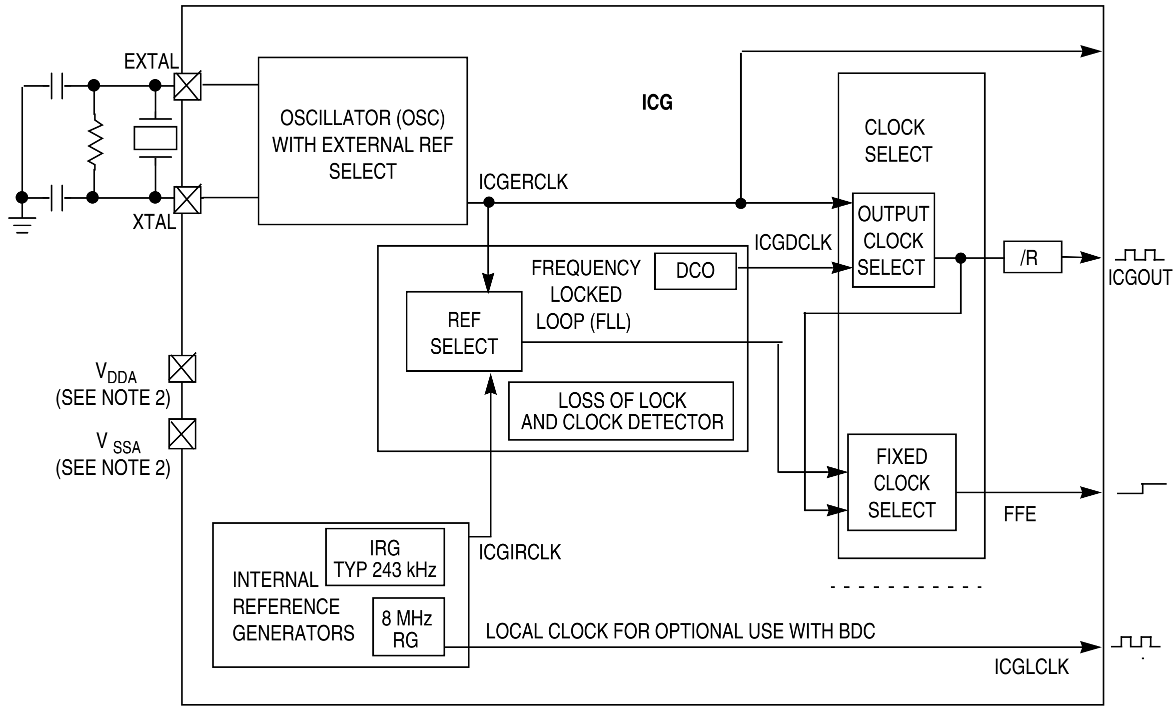
Usually, all system clocks, including the crystal oscillator (when used), are halted during stop mode to minimize power consumption. In such systems, external circuitry is needed to control the time spent in stop mode and to issue a signal to wake up the target MCU when it is time to resume processing. Unlike the earlier M68HC05 and M68HC08 MCUs, the HCS08 can be configured to keep a minimum set of clocks running in stop mode. This optionally allows an internal periodic signal to wake the target MCU from stop mode.

When a host debug system is connected to the background debug pin (BKGD) and the ENBDM control bit has been set by a serial command through the background interface (or because the MCU was reset into active background mode), the oscillator is forced to remain active when the MCU enters stop mode. In this case, if a serial BACKGROUND command is issued to the MCU through the background debug interface while the CPU is in stop mode, CPU clocks will resume and the CPU will enter active background mode where other serial background commands can be processed. This ensures that a host development system can still gain access to a target MCU even if it is in stop mode.

Recovery from stop mode depends on the particular HCS08 and whether the oscillator was stopped in stop mode. Refer to the Modes of Operation chapter for more details.

8.1.3 Block Diagram

Figure 8-3 is a top-level diagram that shows the functional organization of the internal clock generation (ICG) module. This section includes a general description and a feature list.



NOTES:
1. See Table 8-9 for specific use of ICGOUT, FFE, ICGLCLK, ICGERCLK
2. Not all HCS08 microcontrollers have unique supply pins for the ICG. See the device pin assignments.

Figure 8-3. ICG Block Diagram

8.2 External Signal Description

The oscillator pins are used to provide an external clock source for the MCU. The oscillator pins are gain controlled in low-power mode (default). Oscillator amplitudes in low-power mode are limited to approximately 1 V, peak-to-peak.

8.2.1 EXTAL — External Reference Clock / Oscillator Input

If upon the first write to ICGC1, either the FEE mode or FBE mode is selected, this pin functions as either the external clock input or the input of the oscillator circuit as determined by REFS. If upon the first write to ICGC1, either the FEI mode or SCM mode is selected, this pin is not used by the ICG.

8.2.2 XTAL — Oscillator Output

If upon the first write to ICGC1, either the FEE mode or FBE mode is selected, this pin functions as the output of the oscillator circuit. If upon the first write to ICGC1, either the FEI mode or SCM mode is

8.4.4 FLL Engaged Internal Unlocked

FEI unlocked is a temporary state that is entered when FEI is entered and the count error (Δn) output from the subtractor is greater than the maximum n_{unlock} or less than the minimum n_{unlock}, as required by the lock detector to detect the unlock condition.

The ICG will remain in this state while the count error (Δn) is greater than the maximum n_{lock} or less than the minimum n_{lock}, as required by the lock detector to detect the lock condition.

In this state the output clock signal ICGOUT frequency is given by $f_{ICGDCLK}$ / R.

8.4.5 FLL Engaged Internal Locked

FLL engaged internal locked is entered from FEI unlocked when the count error (Δn), which comes from the subtractor, is less than n_{lock} (max) and greater than n_{lock} (min) for a given number of samples, as required by the lock detector to detect the lock condition. The output clock signal ICGOUT frequency is given by $f_{ICGDCLK}$ / R. In FEI locked, the filter value is updated only once every four comparison cycles. The update made is an average of the error measurements taken in the four previous comparisons.

8.4.6 FLL Bypassed, External Clock (FBE) Mode

FLL bypassed external (FBE) is entered when any of the following conditions occur:

- From SCM when CLKS = 10 and ERCS is high
- When CLKS = 10, ERCS = 1 upon entering off mode, and off is then exited
- From FLL engaged external mode if a loss of DCO clock occurs and the external reference remains valid (both LOCS = 1 and ERCS = 1)

In this state, the DCO and IRG are off and the reference clock is derived from the external reference clock, ICGERCLK. The output clock signal ICGOUT frequency is given by $f_{ICGERCLK}$ / R. If an external clock source is used (REFS = 0), then the input frequency on the EXTAL pin can be anywhere in the range 0 MHz to 40 MHz. If a crystal or resonator is used (REFS = 1), then frequency range is either low for RANGE = 0 or high for RANGE = 1.

8.4.7 FLL Engaged, External Clock (FEE) Mode

The FLL engaged external (FEE) mode is entered when any of the following conditions occur:

- CLKS = 11 and ERCS and DCOS are both high.
- The DCO stabilizes (DCOS = 1) while in SCM upon exiting the off state with CLKS = 11.

In FEE mode, the reference clock is derived from the external reference clock ICGERCLK, and the FLL loop will attempt to lock the ICGDCLK frequency to the desired value, as selected by the MFD bits. To run in FEE mode, there must be a working 32 kHz–100 kHz or 2 MHz–10 MHz external clock source. The maximum external clock frequency is limited to 10 MHz in FEE mode to prevent over-clocking the DCO. The minimum multiplier for the FLL, from Table 8-12 is 4. Because 4 X 10 MHz is 40MHz, which is the operational limit of the DCO, the reference clock cannot be any faster than 10 MHz.

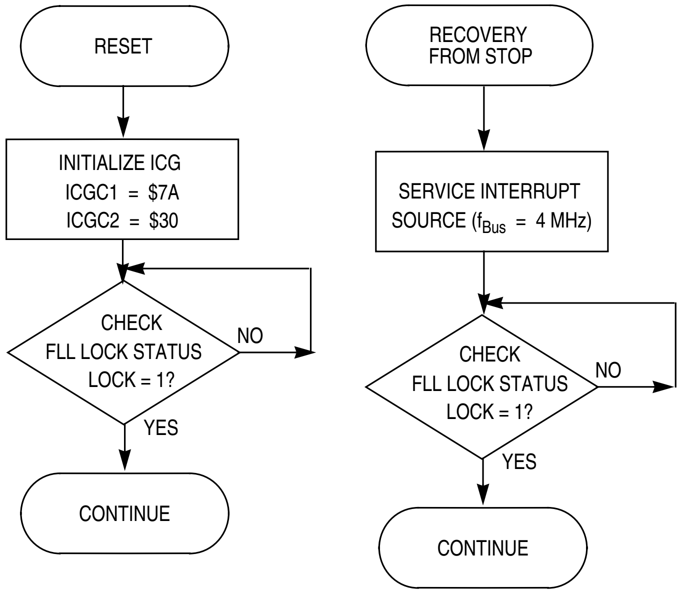


Figure 8-15. ICG Initialization and Stop Recovery for Example #2

9.5.3 KBI Interrupt Controls

The KBF status flag becomes set (1) when an edge event has been detected on any KBI input pin. If KBIE = 1 in the KBI1SC register, a hardware interrupt will be requested whenever KBF = 1. The KBF flag is cleared by writing a 1 to the keyboard acknowledge (KBACK) bit.

When KBIMOD = 0 (selecting edge-only operation), KBF is always cleared by writing 1 to KBACK. When KBIMOD = 1 (selecting edge-and-level operation), KBF cannot be cleared as long as any keyboard input is at its asserted level.

Chapter 10
Timer/PWM (S08TPMV2)

10.1 Introduction

The MC9S08AW60 Series includes two independent timer/PWM (TPM) modules which support traditional input capture, output compare, or buffered edge-aligned pulse-width modulation (PWM) on each channel. A control bit in each TPM configures all channels in that timer to operate as center-aligned PWM functions. In each of these two TPMs, timing functions are based on a separate 16-bit counter with prescaler and modulo features to control frequency and range (period between overflows) of the time reference. This timing system is ideally suited for a wide range of control applications, and the center-aligned PWM capability on the 3-channel TPM extends the field of applications to motor control in small appliances.

The use of the fixed system clock, XCLK, as the clock source for either of the TPM modules allows the TPM prescaler to run using the oscillator rate divided by two (ICGERCLK/2). This option is only available if the ICG is configured in FEE mode and the proper conditions are met (see Section 8.4.11, “Fixed Frequency Clock”). In all other ICG modes this selection is redundant because XCLK is the same as BUSCLK.

10.2 Features

The timer system in the MC9S08AW60 Series includes a 6-channel TPM1 and a separate 2-channel TPM2. Timer system features include:

- A total of eight channels:
  - Each channel may be input capture, output compare, or buffered edge-aligned PWM
  - Rising-edge, falling-edge, or any-edge input capture trigger
  - Set, clear, or toggle output compare action
  - Selectable polarity on PWM outputs
- Each TPM may be configured for buffered, center-aligned pulse-width modulation (CPWM) on all channels
- Clock source to prescaler for each TPM is independently selectable as bus clock, fixed system clock, or an external pin:
  - Prescale taps for divide by 1, 2, 4, 8, 16, 32, 64, or 128
  - External clock inputs TPM1CLK for TPM1 and TPM2CLK for TPM2 (only available in 64-pin package)
- 16-bit free-running or up/down (CPWM) count operation
- 16-bit modulus register to control counter range
- Timer system enable
- One interrupt per channel plus a terminal count interrupt for each TPM module

10.6.3 Channel Event Interrupt Description

The meaning of channel interrupts depends on the current mode of the channel (input capture, output compare, edge-aligned PWM, or center-aligned PWM).

When a channel is configured as an input capture channel, the ELSnB:ELSnA control bits select rising edges, falling edges, any edge, or no edge (off) as the edge that triggers an input capture event. When the selected edge is detected, the interrupt flag is set. The flag is cleared by the 2-step sequence described in Section 10.6.1, “Clearing Timer Interrupt Flags.”

When a channel is configured as an output compare channel, the interrupt flag is set each time the main timer counter matches the 16-bit value in the channel value register. The flag is cleared by the 2-step sequence described in Section 10.6.1, “Clearing Timer Interrupt Flags.”

10.6.4 PWM End-of-Duty-Cycle Events

For channels that are configured for PWM operation, there are two possibilities:

- When the channel is configured for edge-aligned PWM, the channel flag is set when the timer counter matches the channel value register that marks the end of the active duty cycle period.
- When the channel is configured for center-aligned PWM, the timer count matches the channel value register twice during each PWM cycle. In this CPWM case, the channel flag is set at the start and at the end of the active duty cycle, which are the times when the timer counter matches the channel value register.

The flag is cleared by the 2-step sequence described in Section 10.6.1, “Clearing Timer Interrupt Flags.”

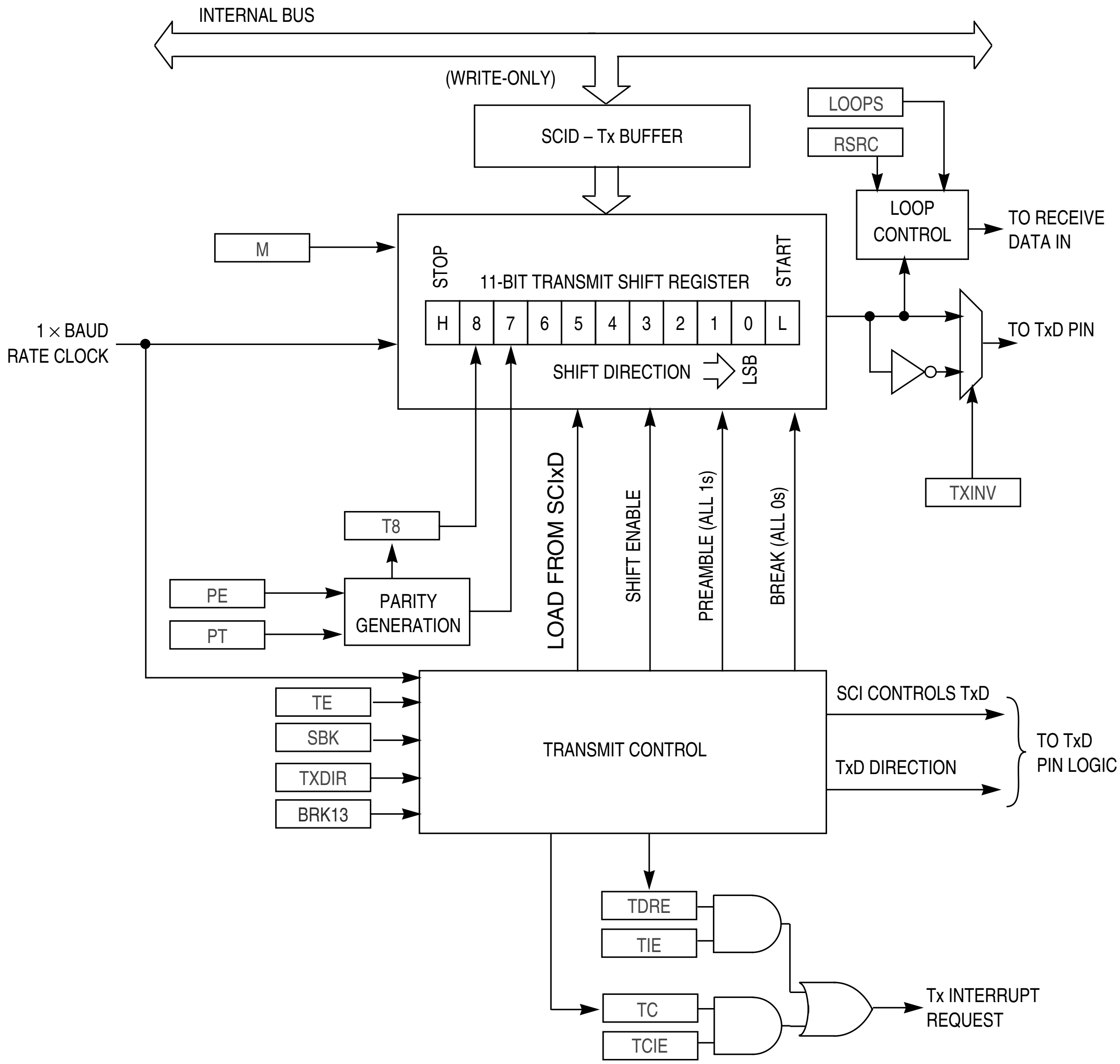


Figure 11-2. SCI Transmitter Block Diagram

Table 11-7. SCIxC3 Register Field Descriptions (continued)

Field	Description
5 TXDIR	**TxD Pin Direction in Single-Wire Mode** — When the SCI is configured for single-wire half-duplex operation (LOOPS = RSRC = 1), this bit determines the direction of data at the TxD pin. 0 TxD pin is an input in single-wire mode. 1 TxD pin is an output in single-wire mode.
4 TXINV[1]	**Transmit Data Inversion** — Setting this bit reverses the polarity of the transmitted data output. 0 Transmit data not inverted 1 Transmit data inverted
3 ORIE	**Overrun Interrupt Enable** — This bit enables the overrun flag (OR) to generate hardware interrupt requests. 0 OR interrupts disabled (use polling). 1 Hardware interrupt requested when OR = 1.
2 NEIE	**Noise Error Interrupt Enable** — This bit enables the noise flag (NF) to generate hardware interrupt requests. 0 NF interrupts disabled (use polling). 1 Hardware interrupt requested when NF = 1.
1 FEIE	**Framing Error Interrupt Enable** — This bit enables the framing error flag (FE) to generate hardware interrupt requests. 0 FE interrupts disabled (use polling). 1 Hardware interrupt requested when FE = 1.
0 PEIE	**Parity Error Interrupt Enable** — This bit enables the parity error flag (PF) to generate hardware interrupt requests. 0 PF interrupts disabled (use polling). 1 Hardware interrupt requested when PF = 1.

[1] Setting TXINV inverts the TxD output for all cases: data bits, start and stop bits, break, and idle.

11.2.7 SCI Data Register (SCIxD)

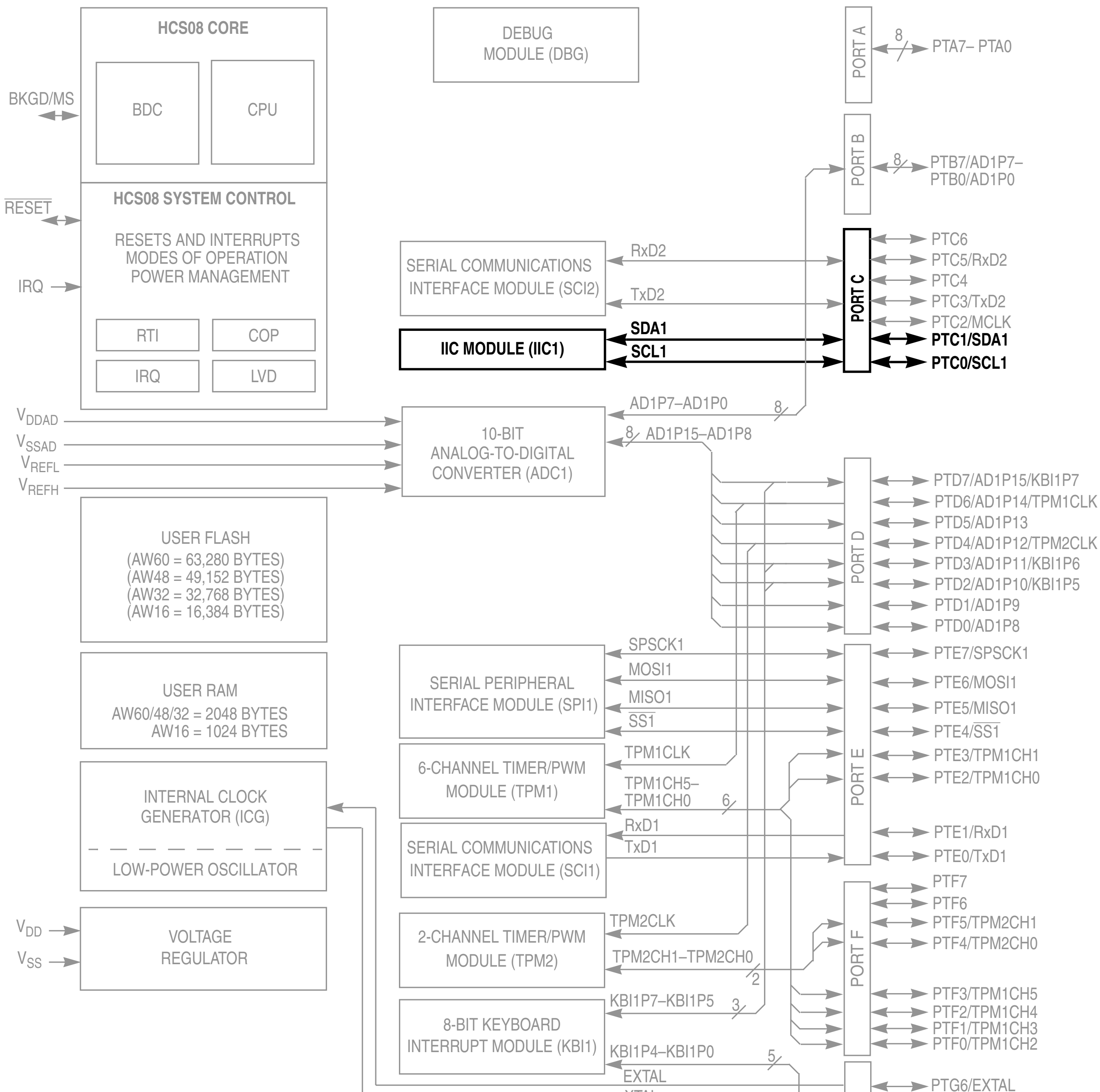
This register is actually two separate registers. Reads return the contents of the read-only receive data buffer and writes go to the write-only transmit data buffer. Reads and writes of this register are also involved in the automatic flag clearing mechanisms for the SCI status flags.

	7	6	5	4	3	2	1	0
R	R7	R6	R5	R4	R3	R2	R1	R0
W	T7	T6	T5	T4	T3	T2	T1	T0
Reset	0	0	0	0	0	0	0	0

Figure 11-11. SCI Data Register (SCIxD)

11.3 Functional Description

The SCI allows full-duplex, asynchronous, NRZ serial communication among the MCU and remote devices, including other MCUs. The SCI comprises a baud rate generator, transmitter, and receiver block. The transmitter and receiver operate independently, although they use the same baud rate generator. During normal operation, the MCU monitors the status of the SCI, writes the data to be transmitted, and processes received data. The following describes each of the blocks of the SCI.



NOTES:
1. Port pins are software configurable with pullup device if input port.
2. Pin contains software configurable pullup/pulldown device if IRQ is enabled (IRQPE = 1). Pulldown is enabled if rising edge detect is selected (IRQEDG = 1)
3. IRQ does not have a clamp diode to V_{DD}. IRQ should not be driven above V_{DD}.
4. Pin contains integrated pullup device.
5. Pins PTD7, PTD3, PTD2, and PTG4 contain both pullup and pulldown devices. Pulldown enabled when KBI is enabled (KBIPEn = 1) and rising edge is selected (KBEDGn = 1).

Figure 13-1. Block Diagram Highlighting the IIC Module

14.7.2 Sources of Error

Several sources of error exist for A/D conversions. These are discussed in the following sections.

14.7.2.1 Sampling Error

For proper conversions, the input must be sampled long enough to achieve the proper accuracy. Given the maximum input resistance of approximately 7kΩ and input capacitance of approximately 5.5 pF, sampling to within 1/4LSB (at 10-bit resolution) can be achieved within the minimum sample window (3.5 cycles @ 8 MHz maximum ADCK frequency) provided the resistance of the external analog source (R_{AS}) is kept below 5 kΩ.

Higher source resistances or higher-accuracy sampling is possible by setting ADLSMP (to increase the sample window to 23.5 cycles) or decreasing ADCK frequency to increase sample time.

14.7.2.2 Pin Leakage Error

Leakage on the I/O pins can cause conversion error if the external analog source resistance (R_{AS}) is high. If this error cannot be tolerated by the application, keep R_{AS} lower than $V_{DDAD} / (2^N * I_{LEAK})$ for less than 1/4LSB leakage error (N = 8 in 8-bit mode or 10 in 10-bit mode).

14.7.2.3 Noise-Induced Errors

System noise which occurs during the sample or conversion process can affect the accuracy of the conversion. The ADC accuracy numbers are guaranteed as specified only if the following conditions are met:

- There is a 0.1 μF low-ESR capacitor from V_{REFH} to V_{REFL}.
- There is a 0.1 μF low-ESR capacitor from V_{DDAD} to V_{SSAD}.
- If inductive isolation is used from the primary supply, an additional 1 μF capacitor is placed from V_{DDAD} to V_{SSAD}.
- V_{SSAD} (and V_{REFL}, if connected) is connected to V_{SS} at a quiet point in the ground plane.
- Operate the MCU in wait or stop3 mode before initiating (hardware triggered conversions) or immediately after initiating (hardware or software triggered conversions) the ADC conversion.
  - For software triggered conversions, immediately follow the write to the ADC1SC1 with a WAIT instruction or STOP instruction.
  - For stop3 mode operation, select ADACK as the clock source. Operation in stop3 reduces V_{DD} noise but increases effective conversion time due to stop recovery.
- There is no I/O switching, input or output, on the MCU during the conversion.

There are some situations where external system activity causes radiated or conducted noise emissions or excessive V_{DD} noise is coupled into the ADC. In these situations, or when the MCU cannot be placed in wait or stop3 or I/O activity cannot be halted, these recommended actions may reduce the effect of noise on the accuracy:

- Place a 0.01 μF capacitor (C_{AS}) on the selected input channel to V_{REFL} or V_{SSAD} (this will improve noise issues but will affect sample rate based on the external analog source resistance).

- Average the result by converting the analog input many times in succession and dividing the sum of the results. Four samples are required to eliminate the effect of a 1LSB, one-time error.
- Reduce the effect of synchronous noise by operating off the asynchronous clock (ADACK) and averaging. Noise that is synchronous to ADCK cannot be averaged out.

14.7.2.4 Code Width and Quantization Error

The ADC quantizes the ideal straight-line transfer function into 1024 steps (in 10-bit mode). Each step ideally has the same height (1 code) and width. The width is defined as the delta between the transition points to one code and the next. The ideal code width for an N bit converter (in this case N can be 8 or 10), defined as 1LSB, is:

$$1LSB = (V_{REFH} - V_{REFL}) / 2^N \qquad \textit{Eqn. 14-2}$$

There is an inherent quantization error due to the digitization of the result. For 8-bit or 10-bit conversions the code will transition when the voltage is at the midpoint between the points where the straight line transfer function is exactly represented by the actual transfer function. Therefore, the quantization error will be ± 1/2LSB in 8- or 10-bit mode. As a consequence, however, the code width of the first ($000) conversion is only 1/2LSB and the code width of the last ($FF or $3FF) is 1.5LSB.

14.7.2.5 Linearity Errors

The ADC may also exhibit non-linearity of several forms. Every effort has been made to reduce these errors but the system should be aware of them because they affect overall accuracy. These errors are:

- Zero-scale error (E_{ZS}) (sometimes called offset) — This error is defined as the difference between the actual code width of the first conversion and the ideal code width (1/2LSB). Note, if the first conversion is $001, then the difference between the actual $001 code width and its ideal (1LSB) is used.
- Full-scale error (E_{FS}) — This error is defined as the difference between the actual code width of the last conversion and the ideal code width (1.5LSB). Note, if the last conversion is $3FE, then the difference between the actual $3FE code width and its ideal (1LSB) is used.
- Differential non-linearity (DNL) — This error is defined as the worst-case difference between the actual code width and the ideal code width for all conversions.
- Integral non-linearity (INL) — This error is defined as the highest-value the (absolute value of the) running sum of DNL achieves. More simply, this is the worst-case difference of the actual transition voltage to a given code and its corresponding ideal transition voltage, for all codes.
- Total unadjusted error (TUE) — This error is defined as the difference between the actual transfer function and the ideal straight-line transfer function, and therefore includes all forms of error.

14.7.2.6 Code Jitter, Non-Monotonicity and Missing Codes

Analog-to-digital converters are susceptible to three special forms of error. These are code jitter, non-monotonicity, and missing codes.

Code jitter is when, at certain points, a given input voltage converts to one of two values when sampled repeatedly. Ideally, when the input voltage is infinitesimally smaller than the transition voltage, the

Appendix A
Electrical Characteristics and Timing Specifications

A.1 Introduction

This section contains electrical and timing specifications.

A.2 Parameter Classification

The electrical parameters shown in this supplement are guaranteed by various methods. To give you a better understanding, the following classification is used and the parameters are tagged accordingly in the tables where appropriate:

Table A-1. Parameter Classifications

P	Those parameters are guaranteed during production testing on each individual device.
C	Those parameters are achieved by the design characterization by measuring a statistically relevant sample size across process variations.
T	Those parameters are achieved by design characterization on a small sample size from typical devices under typical conditions unless otherwise noted. All values shown in the typical column are within this category.
D	Those parameters are derived mainly from simulations.

NOTE

The classification is shown in the column labeled “C” in the parameter tables where appropriate.

A.3 Absolute Maximum Ratings

Absolute maximum ratings are stress ratings only, and functional operation at the maxima is not guaranteed. Stress beyond the limits specified in Table A-2 may affect device reliability or cause permanent damage to the device. For functional operating conditions, refer to the remaining tables in this section.

This device contains circuitry protecting against damage due to high static voltage or electrical fields; however, it is advised that normal precautions be taken to avoid application of any voltages higher than maximum-rated voltages to this high-impedance circuit. Reliability of operation is enhanced if unused inputs are tied to an appropriate logic voltage level (for instance, either V_{SS} or V_{DD}).